



95th ARFTG Microwave Measurement Conference

Microwave and Millimeter-Wave Measurements for the Connected World

Los Angeles, CA, USA, June 26, 2020

www.arftg.org

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CALL FOR PAPERS

The 95th ARFTG Microwave Measurement Conference (which is held as part of IMS week 2020) will be held at the Los Angeles Convention Center with an exciting collection of measurement topics to be presented. The theme for this conference is:

“Microwave and Millimeter-Wave Measurements for the Connected World”.

Technical papers are solicited describing original work in areas of measurement for state-of-the-art and next-generation technologies for communications and sensing including, but not limited to:

- Millimeter-wave measurement techniques for communications and radars
- Millimeter-wave antenna and OTA testing
- Test methods for the manufacture for millimeter-wave and microwave components.

Topics always of interest include:

- RF/digital mixed-signal measurement and calibration
- Nonlinear / Large-signal measurement and modeling techniques
- Terahertz measurement techniques
- Calibration methods
- Materials measurement approaches
- Other topical areas of RF, microwave, millimeter-wave measurements

Deadlines

February 14, 2020

Paper summary due in PDF format.

March 9, 2020

Paper acceptance and classification will be communicated.

March 29, 2020

Publication-ready paper is due in PDF format.

Instructions for Authors

Contributed papers will be presented as 20-minute talks or in an interactive poster session. The final version of the papers will be published in the conference proceedings, and will be submitted as well to IEEE Xplore, provided it has been presented during the conference.

We request that authors submit a 4-page summary paper with supporting figures of both experimental setups and measurement results to enable evaluations of the novelty of the work. More details and submission instructions can be found at:

<http://www.arftg.org/index.php/upcoming-conference/author-instructions>.

This year, ARFTG will also be participating in the Three Minute Thesis (3MT) competition along with IMS and RFIC. Authors of accepted papers will be able to enter this competition with finalists presenting a description of their work for a general audience.

Exhibit & Sponsorship

The 95th ARFTG Microwave Measurement Conference also offers an outstanding exhibition and sponsorship opportunity. Please contact our Exhibits and Sponsorship Chairs (exhibits@arftg.org, sponsorship@arftg.org) directly for further information.



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